

Aerated concrete microwave reflection and transmission properties in a wet environment

Koppel, Tarmo; Vilcane, Inese; Mironovs, Viktors; Shishkin, Andrei; Rubene, Sanita; **Tint, Piia** Vide. Tehnologija. Resursi : XI starptautiskas zinatniski praktiskas konferences materiali 2017. gada 15.-17. junijs. 3. sejums = Environment. Technology. Resources : proceedings of the 11th International Scientific and Practical Conference. Volume III 2017 / p. 145-149 : ill
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Computer aided method for measurement of reflection and impedance characteristics of RF devices

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Londonisse kavandatakse ilma varjuta kõrghoonepaari. Päikese peegeldamine nõuab ettevaatust

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